

## INFORMATION DISCLOSURE

## STATEMENT BY APPLICANT

(use as many sheets as necessary)



Attorney Docket Number	39260/RAG/C766
Application Number	09/547,790
Filing Date	April 12, 2000
Applicant(s)	Francis M. Reininger
Group Art Unit	2877
Examiner Name	To be determined

## U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
GW	4,509,857	04/1985	Vermande	356	346	
GW	4,523,846	06/1985	Breckinridge et al.	356	346	
GW	4,976,542	12/1990	Smith	356	346	
GW	5,059,027	10/1991	Roesler et al.	356	346	
GW	5,768,040	06/1998	Macenka et al.	359	859	
GW	5,777,736	07/1998	Horton	356	346	
GW	5,781,293	07/1998	Padgett et al.	356	346	

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

## OTHER DOCUMENTS

EXAMINER INITIALS	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
GW	Hirst et al., "Optical sensors: a path to better gas detection", Global Challenges, Physics World, August 1998, pp. 37-40
GW	DOHI ET AL., "Attainment of High Resolution Holographic Fourier Transform Spectroscopy", Applied Optics, May 1971, pp 1137-1140, Vol. 10, No. 5
GW	STROKE ET AL., "Fourier-Transform Spectroscopy Using Holographic Imaging Without Computing and With Stationary Interferometers", Physics Letters, June 1, 1965, pp. 272-274, Vol. 16, No. 3
GW	BARNES, "Photodiode array Fourier transform spectrometer with improved dynamic range", Applied Optics, November 15, 1985, pp. 3702-3706, Vol. 24, No. 22,
GW	OKAMOTO ET AL., "Fourier transform spectrometer with a self-scanning photodiode array", Applied Optics, January 15, 1984, pp. 269-273, Vol. 23, No. 2,

EXAMINER SIGNATURE		DATE CONSIDERED	7/23/02
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## U.S. PATENT DOCUMENTS

EXAMINER INITIALS	Cite No. <sup>1</sup>	DOCUMENT NUMBER Number - kind code <sup>2</sup> . (If known)	PUBLICATION DATE MM-DD-YYYY	NAME OF PATENTEE
GW		5,266,795	11/30/1993	Vaughan
GW		5,880,834	03/09/1999	Chrisp

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	Cite No. <sup>1</sup>	Foreign Patent Document Country Code <sup>1</sup> - Number <sup>1</sup> - Kind Code <sup>2</sup> (If known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	T <sup>3</sup> ( <input checked="" type="checkbox"/> )

## OTHER DOCUMENTS

EXAMINER INITIALS	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, — symposium, catalog, etc.), date, page(s), volume-issue-number(s), publisher, city and/or country where published.
GW		FLAMINI, Enrico et al.; <i>Remote mineralogy through multispectral imaging, the VIMS-V instrument</i> ; 10 pp.
GW		LOBB, D.R.; <i>Theory of concentric designs for grating spectrometers</i> ; Applied Optics; May 1, 1994; Vol. 33, No. 13, pp. 2648-2658
GW		MERTZ, L.; <i>Concentric spectographs</i> ; Applied Optics; December 1977; Vol. 16, No. 12; pp. 3122-3124
GW		OFFNER, A.; <i>New Concepts in Projection Mask Aligners</i> ; Optical Engineering; March-April 1975; Vol. 14, No. 2; pp. 130-132
GW		REININGER, Francis; <i>Near ultraviolet visible infrared mapping spectrometer (NU-VIMS)</i> ; SPIE; 1994; Vol. 2209; pp. 332-344

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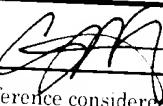
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GW		REININGER, Francis; VIRTIS: <i>Visible Infrared Thermal Imaging Spectrometer for the Rosetta mission</i> ; SPIE; 1996; Vol. 2819; pp. 66-77
GW		REININGER; Francis et al.; <i>Visible infrared mapping spectrometer-visible channel (VIMS-V)</i> ; SPIE; 1994; Vol. 2198; pp. 239-250

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